

# SAMXON BRAND ALUMINUM ELECTROLYTIC CAPACITORS PRODUCT SPECIFICATION 規格書

CUSTOMER: (客戶): DATE: (日期):2018-06-06

CATEGORY (品名)	: ALUMINUM ELECTROLYTIC CAPACITORS
DESCRIPTION (型号)	: RT 250V33μF(φ10X20)
VERSION (版本)	: 01
Customer P/N	:
SUPPLIER	:

SUPPL	IER	CUS	TOMER
PREPARED (拟定)	CHECKED (审核)	APPROVAL (批准)	SIGNATURE (签名)
孟庆庆	付婷婷		

### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

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N o.	SAMXON Part No.		Gan	Cap. tolerance	Temp. range(°C)		Leakage Current (μA,2min)	* If it is flat r	ubber, tl	here is no Dim			e flat rubbe

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### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

# SAMXON

### 1. Application

This specification applies to polar Aluminum electrolytic capacitor (foil type) used in electronic equipment. Designed capacitor's quality meets IEC60384.

### Part Number System 2. 4 5 6 7 89 101112 1314 123 1516 17 тс Ρ EGS 1 5 D11 S 0 м 1 н TOL SAMXON SLEEVE PRODUCT LINE MATERIAL SERIES CAPACITANCE VOLTAGE CASE SIZE TYPE Cap(MFD) Tolerance (%) Code Voltage (W.V.) Code Code Case Size Feature Code SAMXON Product Li ries ESM EKF ESS EKS EGS EKM EKG EOM EZM EZS 0D (4) Co 3 B 5 1 4 C 5 D 3 E RR For internal use only Radial bulk 0.1 104 ± 5 J 2.5 0E (The product lines 4 0G we have H.A.B.C.D. Ammo Taping 0.22 224 6.3 OJ к E,M or 0,1,2,3,4,5,9) ±10 0K 8 0.33 334 2.0mm Pitch тτ 10 1A ±15 L JV4AK7L8MN 12.5 1B 2.5mm Pitch τu 0.47 474 1C 16 EG м 1D ±20 20 105 3.5mm Pitch тν C FG 1 Sleeve Material 46 46.5 18 18.5 20 22 7 EGE 25 1E PET Р 11 5.0mm Pitch тс 30 2.2 225 Ν ±30 32 13 ERS ERF ERL ERR Lead Cut & Form 35 3.3 335 1V -40 w 22 25 30 34 35 40 42 45 40 1G OP WQ R 46S T U 8X Z СВ-Туре СВ 4.7 475 42 1M -20 0 А FR 50 1H ERE ERD ERH EBD СЕ-Туре CE 10 106 57 1L -20 +10 С 63 1J HE-Type HE 22 226 71 **1**S 51 3.5 76 80 ER. 75 1**T** 6 ERE ERC EFA ENP -20 +40 × KD-Type ĸD 336 33 80 1K 85 1R 90 100 -20 +50 FD-Type FD s Z Costing Ex 454 05 7 77 11 11 11 12 12 12 12 12 12 12 12 12 13 13 13 13.5 1C 20 20.5 7 30.7 75 47 476 90 19 ENH ERV ERV ELP EAP EOP 100 2A -10 0 ЕН-Туре EΗ в 107 100 120 20 125 2B PCB Termial -10 +20 220 227 v 150 2Z 160 2C sw 330 337 -10 +30 Q 180 2P 200 2D Snap-in SX EKP EEP 470 477 -10 +50 215 22 т EFP ESP 220 2N 1C 20 25 2J 30 3A 35 3E sz 2200 228 -5 +10 230 23 Е EVP EGP EWR EWU EWT EWS EWF EWS EWH EWL EWB 250 2E Lug SG 22000 229 -5 +15 275 2Т F 05 300 21 33000 339 310 2R -5 +20 3 G 06 315 2F 50 80 1L 1K 1M 1P 47000 479 330 2U 0 +20 R Т5 2V 350 100000 10T Screw 360 2X 0 +30 0 т6 VNS 375 2Q 150000 15T 40 50 55 10 1R 1E 1S 1F 1T 1U 0 +50 385 2Y I. D5 400 2G 220000 22T +5 +15 2M z 420 D6 VZS 450 2W 330000 ззт +5 D 500 2H 1000000 550 25 10M +10 +50 26 Y 600 2J 1500000 15M 630 +10+30 н 2200000 22M 3300000 33M 5

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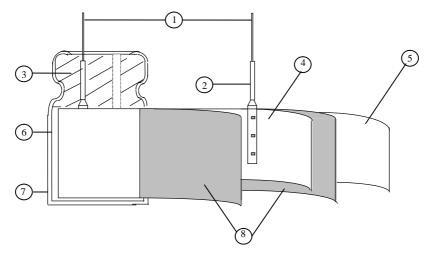
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### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

# SAMXON

### 3. Construction

Single ended type to be produced to fix the terminals to anode and cathode foil, and wind together with paper, and then wound element to be impregnated with electrolyte will be enclosed in an aluminum case. Finally sealed up tightly with end seal rubber, then finished by putting on the vinyl sleeve.



	Component	Material
1	Lead line	Tinned CP wire (Pb Free)
2	Terminal	Aluminum wire
3	Sealing Material	Rubber
4	Al-Foil (+)	Formed aluminum foil
5	Al-Foil (-)	Etched aluminum foil or formed aluminum foil
6	Case	Aluminum case
7	Sleeve	РЕТ
8	Separator	Electrolyte paper

### 4. Characteristics

Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurements and tests are as follows:

Ambient temperature	:15°C to 35°C
Relative humidity	: 45% to 85%
Air Pressure	: 86kPa to 106kPa

If there is any doubt about the results, measurement shall be made within the following conditions:

Ambient temperature	$: 20^{\circ}C \pm 2^{\circ}C$
Relative humidity	: 60% to 70%
Air Pressure	: 86kPa to 106kPa

### Operating temperature range

The ambient temperature range at which the capacitor can be operated continuously at rated voltage See table 1 temperature range.

As to the detailed information, please refer to table 2.

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### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

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	ITEM	PERFORMANCE
	Rated voltage (WV)	
4.1		WV (V.DC) 160 200 220 250 350 400 420 450
	Surge voltage (SV)	SV (V.DC)         200         250         270         300         400         450         470         500
4.2	Nominal capacitance (Tolerance)	$<$ Condition>Measuring Frequency: 120Hz±12HzMeasuring Voltage: Not more than 0.5VrmsMeasuring Temperature: $20\pm2^{\circ}C$ $<$ Criteria>Shall be within the specified capacitance tolerance.
4.3	Leakage current	<b><condition></condition></b> Connecting the capacitor with a protective resistor $(1k \Omega \pm 10 \Omega)$ in series for 2 minutes, and then, measure Leakage Current. <b><criteria></criteria></b> Refer to Table 1
4.4	tan δ	<condition> See 4.2, Norm Capacitance, for measuring frequency, voltage and temperature. <criteria> Refer to Table 1</criteria></condition>
4.5	Terminal strength	<condition> Tensile Strength of Terminals Fixed the capacitor, applied force to the terminal in lead out direction for <math>10 \pm 100</math> seconds. Bending Strength of Terminals. Fixed the capacitor, applied force to bent the terminal (1~4 mm from the rubber) fo 90° within 2~3 seconds, and then bent it for 90° to its original position within 2~3 seconds.Diameter of lead wireTensile force N (kgf)Bending force N (kgf)0.5mm and less5 (0.51)2.5 (0.25)Over 0.5mm to 0.8mm10 (1.0)5 (0.51)<criteria> No noticeable changes shall be found, no breakage or looseness at the terminal.</criteria></condition>

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### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

			<condition></condition>	1		1			
4.6 $2$ $40(-25) \pm 3$ Time to reach thermal equilibrium $3$ $20\pm 2$ Time to reach thermal equilibrium $4$ 4.6 $3$ $20\pm 2$ Time to reach thermal equilibrium $5$ $20\pm 2$ Time to reach thermal equilibrium4.6 $3$ $20\pm 2$ Time to reach thermal equilibrium4.6 $5$ $1$ tan $\delta$ shall be within the limit of Item 4.4The leakage current measured shall no more than 8 times of its specified value. $0$ $1$ tan $\delta$ shall be within the limit of Item 4.4The leakage current shall no more than 8 times of its specified value. $c$ $A$ <td></td> <td></td> <td>STEP</td> <td>Testing Tempe</td> <td>rature(°C)</td> <td></td> <td></td> <td></td> <td></td>			STEP	Testing Tempe	rature(°C)				
4.6 Temperature characteristi cs 4.6 Load 4.7 Load 4.7 Load 5. Load 5. Load 5. Load 4.7 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 5. Shelf 5. Shelf Shelf 4.8 Shelf 4.8 Shelf Shelf Shelf 1. Shelf				20±2	2			-	
4 $105\pm2$ Time to reach thermal equilibrium         5 $20\pm2$ Time to reach thermal equilibrium         4.6       5 $20\pm2$ Time to reach thermal equilibrium         4.6       a. tan $\delta$ shall be within the limit of Item 4.4The leakage current measured shall no more than 8 times of its specified value.       b. In step 5, tan $\delta$ shall be within the limit of Item 4.4The leakage current shall no more than the specified value.         c. At-40°C (-25°C), impedance (2) ratio shall not exceed the value of the following table.       Working Voltage (V) 160 200 250 350 400 42         2-25°C/Z+20°C       3       3       5       5         For capacitance value > 1000 µ F, Add 0.5 per another 1000 µ F for Z-25/Z+20°C, Add 1.0 per another 1000 µ F for Z-40°C/Z+20°C Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz.         4.7       Load       If       Steff test         4.7       Load       If       Cand ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table:       -Criteria>         4.7       Load       If       Eakage current       Value in 4.3 shall be satisfied         4.7       Load       If       Eakage current       Value in 4.3 shall be satisfied         4.7       If       If       The characteristic shall meet the following requireme			2	-40(-25)	$\pm 3$	Time to rea	ich thermal ea	quilibrium	ı
4.6 $5$ $20\pm 2$ Time to reach thermal equilibrium         4.6 $5$ $20\pm 2$ Time to reach thermal equilibrium         4.6 $c$ an $\delta$ shall be within the limit of Item 4.4The leakage current measured shall no more than 8 times of its specified value.       b. In step 5, tan $\delta$ shall be within the limit of Item 4.4The leakage current shall no more than the specified value.         c. At-40°C (-25°C), impedance (z) ratio shall not exceed the value of the following table. $v$ At-40°C (-25°C), impedance (z) ratio shall not exceed the value of the following table.         Working Voltage (V)       160       200       250       350       400       42         Working Voltage (V)       160       200       250       350       400       42         Working Voltage (V)       160       0.00 $F$ or $Z$ -25°C/2+20°C, Add 1.0 per another 1000 $\mu$ F for Z-25/Z+20°C, Add 1.0 per another 1000 $\mu$ F for Z-40°C/Z+20°C       Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz.         4.7       Load       Stordino>       According to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C $\pm 2$ with DC bias voltage plus the rated irple current for Table 1. (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then to product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table:         4.7       Load       Iffe test       Icaaacteristic shall meet the follow			3	20±	2	Time to rea	ich thermal ea	quilibrium	l
4.6 Criteria> a. tan $\delta$ shall be within the limit of Item 4.4The leakage current measured shall no more than 8 times of its specified value. b. In step 5, tan $\delta$ shall be within the limit of Item 4.4The leakage current shall no more than 8 times of its specified value. c. At-40°C (-25°C), impedance (z) ratio shall not exceed the value of the following table. Working Voltage (V) 160 200 250 350 400 44 Z-25°C/Z+20°C 3 3 3 5 5 0 For capacitance value > 1000 $\mu$ F, Add 0.5 per another 1000 $\mu$ F for Z-25/Z+20°C. Add 1.0 per another 1000 $\mu$ F for Z-40°C/Z+20°C Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz. 4.7 Load If test Load If test Load If test Load Shelf A.8 Shelf If test Shelf A.8 Shelf If test Shelf A.8 Shelf If test Shelf A.8 Shelf A.8 Shelf A.8 Shelf A.8 Shelf A.8 Shelf A.8 Shelf If test Shelf A.8 Shelf A.8 Shelf If test Criteria> Criteria> Criteria> Criteria> Criteria> Condition> Cand then, tested to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta A.8 Shelf shelf shell be connected to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta A.8 Shelf shall be connected to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta A.8 Shelf shall be connected to a series limiting resistor(1k ± 100 Ω) with D.C. rated volta A predictions appliced in 30min. After which the capacitors shall be discharged, and then, tested to 30min. After			4	$105 \pm$	2	Time to rea	ich thermal ea	quilibrium	l I
4.6       a. tan δ shall be within the limit of Item 4.4The leakage current measured shall no more than 8 times of its specified value.       b. In step 5, tan δ shall be within the limit of Item 4.4The leakage current shall no more than 8 times of its specified value.         4.6       c. At-40°C (-25°C), impedance (z) ratio shall not exceed the value of the following table.         Working Voltage (V)       160       200       250       350       400       42         2.5°CZ+20°C       3       3       5       5       0         For capacitance value > 1000 μ F, Add 0.5 per another 1000 μ F for Z-25/Z+20°C, Add 1.0 per another 1000 μ F for Z-40°C/Z+20°C       Capacitance, tan δ, and impedance shall be measured at 120Hz.         4.7       Load life test       According to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C ± 2 with DC bias voltage plus the rated ripple current for Table 1. (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following requirements.         4.7       Leakage current ≤ Not more than 200% of the specified value.         4.7       Load life test       Capacitance Change Within ± 20% of initial value.         4.7       Load life       Shelf Not more than 200% of the specified value.         4.7       Load life       The characteristic shall meet the following requirements.         4.8       Load ripple peak voltage			5	$20\pm$	2	Time to rea	ich thermal ea	quilibrium	ı
more than 8 times of its specified value. b. In step 5, tan $\delta$ shall be within the limit of Item 4.4The leakage current shall no more than the specified value. c. At-40°C (-25°C), impedance (z) ratio shall not exceed the value of the following table.4.6Working Voltage (V)160200250350400442.25°C/Z+20°C33556For capacitance value > 1000 µ F, Add 0.5 per another 1000 µ F for Z-25/Z+20°C, Add 1.0 per another 1000 µ F for Z-25/Z+20°CAdd 1.0 per another 1000 µ F for Z-240°C/Z+20°CCapacitance, tan $\delta$ , and impedance shall be measured at 120Hz.Condition>4.7Load life testCondition>4.7Load life testLeakage current $\Delta$ cording to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C ± 2 with DC bias voltage plus the rated ripple current for Table 1. (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should meet the following table:       Criteria>Leakage current Capacitance Change Within ±20% of initial value. tan $\delta$ Not more than 200% of the specified value.        									
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$\begin{array}{c c c c c c c c c c c c c c c c c c c $		Temperature		-				_	
4.6 cs Infore than the specified value. c. At-40°C (-25°C), impedance (z) ratio shall not exceed the value of the following table: $\frac{Working Voltage (V) 160 200 250 350 400 42}{Z-25°C/Z+20°C, 3 3 3 5 5 0}$ For capacitance value > 1000 µ F, Add 0.5 per another 1000 µ F for Z-25/Z+20°C, Add 1.0 per another 1000 µ F for Z-40°C/Z+20°C Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz. 4.7 Load 4.7 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.6 Load 4.6 Load 4.7 Load 4.6 Load 4.7 Load 4.7 Load 4.7 Load 4.8 Load 4.6 Load 4.7 Load 4.6 Load 4.7 Load 4.7 Load 4.7 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.6 Load 4.7 Load 4.7 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.6 Load 4.7 Load 4.7 Load 4.7 Load 4.8 Load 4.8 Load 4.8 Load 4.8 Load 4.6 Load 4.7 Load 4.6 Load 4.7 Load 4.7 Load 4.8 Load 4.8 Load 4.8 Load 4.6 Load 4.7 Load 4.6 Load 4.7 Load 4.8 Load 4.8 Load 4.6 Load 4.7 Load 4.6 Load 4.6 Load 4.7 Load 4.6 Load 4.7 Load 4.7 Load 4.7 Load 4.7 Load 4.6 Load 4.7 Load 4.6 Load 4.7 Load 4.7 Load 4.7 Load 4.7 Load 4.7 Load 4.8 Load 4.8 Load 4.7 Load 4.8 Load 4.6 Load 4.6 Load 4.7 Load 4.8 Load 4.8 Load 4.8 Load 4.6 Load 4.7 Load 4.8 Load 4.8 Load 4.7 Load 4.7 Load 4.7 Load 4.8 Load 4.7 Load 4.8 Load 4.8 Load 4.7		-	-		nin the limit	t of Item 4.4	The leakage of	current sh	all not
table.Working Voltage (V)16020025035040044Z-25°C/Z+20°C333556For capacitance value > 1000 $\mu$ F, Add 0.5 per another 1000 $\mu$ F for Z-25/Z+20°C, Add 1.0 per another 1000 $\mu$ F for Z-40°C/Z+20°CCapacitance, tan $\delta$ , and impedance shall be measured at 120Hz.4.7Load </td <td>4.6</td> <td></td> <td></td> <td>-</td> <td>(_)</td> <td>- 11</td> <td>1 41 1</td> <td>6 41 <b>6</b> - 11</td> <td></td>	4.6			-	(_)	- 11	1 41 1	6 41 <b>6</b> - 11	
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$				25 C), impedance	(z) ratio sn	all not excee	d the value of	t the follo	wing
4.7       If a big					200	250	350	400	450
4.7       Load         Condition>         4.7       Load <td></td> <td></td> <td>Z-25°C/Z+20</td> <td>)°C 3</td> <td>3</td> <td>3</td> <td>5</td> <td>5</td> <td>6</td>			Z-25°C/Z+20	)°C 3	3	3	5	5	6
4.7 Load if $e^{-1}$ if $e^{-1}$ 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 4.8 Shelf 1. Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz. Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz. Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz. Capacitance, tan $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ , and impedance shall be measured at 120Hz. Capacitance $\delta$ and the statistical capacitance $\delta$ initial value. The capacitance $\delta$ initial value. There shall be no leakage of electrolyte. Capacitance $\delta$ in the voltage applied at a temperature of $105 \pm 2^{\circ}C$ for $1000 + 480$ hours. Following this period the capacitors shall be removed from the tachaber and be allowed to stabilized at room temperature for 4-8 hours. Next the shall be connected to a series limiting resistor( $1k \pm 100 \Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to a series limiting resistor( $1k \pm 100 \Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the shall be discharged, and then, tested to the shall be discharged and then the shall be discharged and then, tested to the specified to a specified the capacitors shall be discharged, and then, tested to the specified the capacitors shall be discharged, and then, tested to the specified the capacitors shall be discharged, and then, tested to the specified to a specified the capacitors shall be discharged to the specified the capacitors that the there the table the table there the table there there there t			For capacitanc	e value > 1000 $\mu$		-			
4.7       Load       -Condition>         4.7       Load       According to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C $\pm 2$ with DC bias voltage plus the rated ripple current for Table 1. (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following requirements.         4.7       life test       -Criteria>         The characteristic shall meet the following requirements.       -Criteria>         The characteristic shall meet the following requirements.       -Criteria>         Appearance       Within $\pm 20\%$ of initial value. $\tan \delta$ Not more than 200% of the specified value.         Appearance       There shall be no leakage of electrolyte.         4.8       life       shelf on use stored with no voltage applied at a temperature of $105 \pm 2$ °C for $1000 + 48/0$ hours. Following this period the capacitors shall be removed from the te chamber and be allowed to stabilized at room temperature for 4~8 hours. Next th shall be connected to a series limiting resistor( $1k \pm 100  \Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested t					-			∠-40°C/Z+	20℃.
4.7Load life testAccording to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C $\pm 2$ with DC bias voltage plus the rated ripple current for Table <b>1</b> . (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table:  <b>Criteria&gt;</b> The characteristic shall meet the following requirements.Leakage currentValue in 4.3 shall be satisfied Capacitance ChangeLeakage currentValue in 4.3 shall be satisfied Capacitance ChangeAppearanceThere shall be no leakage of electrolyte. <b>Condition&gt;</b> The capacitors are then stored with no voltage applied at a temperature of $105 \pm 2^{\circ}$ C f 1000+48/0 hours. Following this period the capacitors shall be removed from the te chamber and be allowed to stabilized at room temperature for 4~8 hours. Next th shall be connected to a series limiting resistor(1k±100 $\Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested te			Capacitance, ta	n $\delta$ , and impedat	nce shall be	measured at	120Hz.		
4.7Load life testAccording to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C $\pm 2$ with DC bias voltage plus the rated ripple current for Table <b>1</b> . (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table:  <b>Criteria&gt;</b> The characteristic shall meet the following requirements.Leakage currentValue in 4.3 shall be satisfied Capacitance ChangeLeakage currentValue in 4.3 shall be satisfied Capacitance ChangeAppearanceThere shall be no leakage of electrolyte. <b>Condition&gt;</b> The capacitors are then stored with no voltage applied at a temperature of $105 \pm 2^{\circ}$ C f 1000+48/0 hours. Following this period the capacitors shall be removed from the te chamber and be allowed to stabilized at room temperature for 4~8 hours. Next th shall be connected to a series limiting resistor(1k±100 $\Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested te									
4.7Load life testAccording to IEC60384-4No.4.13 methods, The capacitor is stored at a temperature 105°C $\pm 2$ with DC bias voltage plus the rated ripple current for Table <b>1</b> . (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table:   <b>Criteria&gt;</b> The characteristic shall meet the following requirements.Leakage currentValue in 4.3 shall be satisfied Capacitance Change Within $\pm 20\%$ of initial value. tan $\delta$ Not more than 200% of the specified value. Appearance4.8Shelf life4.8Shelf life									
4.7Load life test $105^{\circ}C \pm 2$ with DC bias voltage plus the rated ripple current for Table <b>1</b> . (The sum DC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table: 4.7life test <b>Criteria&gt;</b> The characteristic shall meet the following requirements.Leakage current Capacitance Change tan $\delta$ AppearanceValue in 4.3 shall be satisfied Capacitance Change Within $\pm 20\%$ of initial value. There shall be no leakage of electrolyte.4.8Shelf life <b>Condition&gt;</b> The capacitors are then stored with no voltage applied at a temperature of $105\pm2^{\circ}C$ f $1000+48/0$ hours. Following this period the capacitors shall be removed from the to chamber and be allowed to stabilized at room temperature for 4~8 hours. Next th shall be connected to a series limiting resistor( $1k\pm100^{\circ}\Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the shall be discharged, and then, tested to				EC60384-4No 4	13 methods	The capacit	or is stored at	atempera	ature of
4.7Load life testDC and ripple peak voltage shall not exceed the rated working voltage) Then t product should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table: 4.7life test </td <td></td> <td></td> <td></td> <td></td> <td></td> <td>-</td> <td></td> <td>-</td> <td></td>						-		-	
4.7Load life testproduct should be tested after 16 hours recovering time at atmospheric conditions. T result should meet the following table:   <b>Criteria&gt;</b> The characteristic shall meet the following requirements.Leakage currentValue in 4.3 shall be satisfied Capacitance Change Within $\pm 20\%$ of initial value. tan $\delta$ Not more than 200% of the specified value. Appearance4.8Shelf life4.8Shelf life				•	-				
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$tan \delta$ Not more than 200% of the specified value.         Appearance       There shall be no leakage of electrolyte.         Shelf       Shelf         4.8       life    Not more than 200% of the specified value.          Appearance       There shall be no leakage of electrolyte.           Appearance           Shelf			Leakage	e current	Value in 4	.3 shall be sa	tisfied		
Appearance       There shall be no leakage of electrolyte.         Appearance       There shall be no leakage of electrolyte.         Condition>       Condition>         The capacitors are then stored with no voltage applied at a temperature of 105±2°C from the temperature of 1000+48/0 hours. Following this period the capacitors shall be removed from the temperature for 4~8 hours. Next the chamber and be allowed to stabilized at room temperature for 4~8 hours. Next the shall be connected to a series limiting resistor(1k±100 Ω) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the capacitors shall be discharged.			Capacit	ance Change	Within $\pm 2$	20% of initia	l value.		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $			tan δ		Not more t	han 200% of	the specified	l value.	
4.8The capacitors are then stored with no voltage applied at a temperature of $105 \pm 2^{\circ}$ C f1000+48/0 hours. Following this period the capacitors shall be removed from the term chamber and be allowed to stabilized at room temperature for 4~8 hours. Next th shall be connected to a series limiting resistor( $1k \pm 100^{\circ}$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the statement of the capacitor shall be discharged.			Appeara	ance	There shall	l be no leaka	ge of electrol	yte.	
4.8The capacitors are then stored with no voltage applied at a temperature of $105 \pm 2^{\circ}$ C f1000+48/0 hours. Following this period the capacitors shall be removed from the term chamber and be allowed to stabilized at room temperature for 4~8 hours. Next th shall be connected to a series limiting resistor( $1k \pm 100^{\circ}$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the statement of the capacitor shall be discharged.			Condition						
<ul> <li>4.8</li> <li>1000+48/0 hours. Following this period the capacitors shall be removed from the techniber and be allowed to stabilized at room temperature for 4~8 hours. Next the shall be connected to a series limiting resistor(1k±100 Ω) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the shall be discharged at the shall</li></ul>				are then stored w	th no voltag	e applied at	a temperature	of $105 \pm 3$	2℃ for
4.8 chamber and be allowed to stabilized at room temperature for $4 \sim 8$ hours. Next the shall be connected to a series limiting resistor( $1k \pm 100 \Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested to the series shall be discharged at the series of the series shall be discharged.			-		•		-		
4.8 Shelf shall be connected to a series limiting resistor( $1k \pm 100 \Omega$ ) with D.C. rated volta applied for 30min. After which the capacitors shall be discharged, and then, tested t				•	-	-			
4.8 life applied for 30min. After which the capacitors shall be discharged, and then, tested t		Shelf				-			-
test characteristics.	4.8	life			•				•
		test							

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### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

		<criteria></criteria>	
			meet the following requirements.
	Shalf	Leakage current	Value in 4.3 shall be satisfied
4.8	Shelf life	Capacitance Change	Within $\pm 20\%$ of initial value.
4.0	test	tan δ	Not more than 200% of the specified value.
	test	Appearance	There shall be no leakage of electrolyte.
		Remark: If the capacitors ar	e stored more than 1 year, the leakage current may
		increase. Please apply voltage	ge through about 1 k $\Omega$ resistor, if necessary.
		<condition></condition>	
			he capacitor connected with a $(100 \pm 50)/C_R (k\Omega)$ resiston
		-	itted to 1000 cycles, each consisting of charge of $30\pm5s$
		followed discharge of 5 mir	
		The test temperature shall	
		C <sub>R</sub> :Nominal Capacitance	(μF)
4.9	Surge	<criteria></criteria>	Not more than the survey of a dama has
4.9	test	Leakage current	Not more than the specified value.
		Capacitance Change	Within $\pm 15\%$ of initial value.
		tan δ	Not more than the specified value.
		Appearance	There shall be no leakage of electrolyte.
		Attention:	
			age at abnormal situation only. It is not applicable to such
		over voltage as often applie	d.
		perpendicular directions. Vibration frequency i Peak to peak amplitud Sweep rate Mounting method: The capacitor with diameter in place with a bracket.	•
4.10	Vibration test	4mm or le	ss Within 30°
4.10		<criteria></criteria>	
4.10		<criteria></criteria>	ss To be soldered ving items shall be tested: No intermittent contacts, open or short
4.10		<criteria></criteria>	ss To be soldered ving items shall be tested: No intermittent contacts, open or short circuiting. No damage of tab terminals or
4.10		<criteria> After the test, the follow</criteria>	ss To be soldered ving items shall be tested: No intermittent contacts, open or short circuiting. No damage of tab terminals or electrodes.
4.10		<criteria> After the test, the follow Inner construction</criteria>	ss To be soldered ving items shall be tested: No intermittent contacts, open or short circuiting. No damage of tab terminals or electrodes. No mechanical damage in terminal. No leakage
4.10		<criteria> After the test, the follow</criteria>	ss To be soldered ving items shall be tested: No intermittent contacts, open or short circuiting. No damage of tab terminals or electrodes.

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### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

	1				
		<condition></condition>			
		The capacitor shall be test		conditions:	
		Soldering temperature	: 245±3°C		
	Solderability	Dipping depth	: 2mm	,	
4.11	test	Dipping speed	: 25±2.5mm	ı/s	
	test	Dipping time	: 3±0.5s		
		<criteria></criteria>			1 .
		Coating quality	immersed	n of 95% of the surface	being
			minersed		
		<condition></condition>			
		Terminals of the capac	itor shall be immersed i	into solder bath at	
		$260\pm5$ °C for $10\pm1$ sec	onds or $400 \pm 10^{\circ}$ C for 3	$^{+1}_{-0}$ seconds to 1.5~2.0n	nm from the
		body of capacitor.		Ū	
	Resistance to	• •	ll be left under the norm	al temperature and norn	nal humidity
4.12	solder heat	for 1~2 hours before n		I	
	test	<criteria></criteria>			
		Leakage current	Not more than the	specified value.	7
		Capacitance Change	Within $\pm 10\%$ of	initial value.	
		tan δ	Not more than the		
		Appearance	There shall be no	leakage of electrolyte.	
		<condition></condition>			
		Temperature Cycle:Accor	ding to IEC60384-4No	4.7 methods, capacitor	shall be
		placed in an oven, the cor			
		Те	Time		
		(1)+20°℃	1	≤3 Minutes	
	~	(2)Rated low tempera	ature (-40°C) (-25°C)	$30\pm 2$ Minutes	
4.12	Change of	(3)Rated high temper		$30\pm 2$ Minutes	
4.13	temperature test	(1) to (3)=1 cycle, tot		50±2 Minutes	
	iest	< <u>Criteria&gt;</u>			
		The characteristic shall m	eet the following requir	ement	
		Leakage current	Not more than the		1
		$\tan \delta$	Not more than the s	*	
		Appearance		eakage of electrolyte.	
				unage of electrolyte.	J
		<condition></condition>			
		Humidity Test:	ANo 1 10 methoda	agitor shall	
		According to IEC60384 be exposed for $500\pm 8$	-		
		$40\pm2^{\circ}$ °C, the characteri			nt
		$40\pm2$ °, the characteri	sue change shan meet t	ne tonowing requireme	
	Damp heat	< Cristania >			
4.14	test	< <u>Criteria&gt;</u>	Not more they the	aified value	
		Leakage current	Not more than the spe		
		Capacitance Change	Within $\pm 20\%$ of init		
		$\tan \delta$	Not more than 120% of	-	
		Appearance	There shall be no leak	age of electrolyte.	

### ELECTROLYTIC CAPACITOR SPECIFICATION RT SERIES

4.15	Vent test	<condition>         The following test only apple         with vent.         D.C. test         The capacitor is connected         current selected from below         <table 3="">         Diameter (mm)       DC         22.4 or less         Over 22.4</table></condition>	with its p v table is <u>Current (</u> <u>1</u> <u>10</u> no dange	polarity reve applied.	ersed to a I	DC power sou	rce. Then a
4.16	Maximum permissible (ripple current)	<condition>The maximum permissible at 120Hz and can be appl Table-1The combined value of D rated voltage and shall notFrequency Multipliers:<math>\boxed{Coefficient}</math><math>\boxed{Hz}</math><math>Cap. (\mu F)</math><math>1 \sim 5.6</math><math>6.8 \sim 180</math><math>220 \sim</math></condition>	ied at ma .C voltag	ximum oper e and the pe	rating temp	erature	exceed the

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# 5. It refers to the latest document of "Environment-related Substances standard" (WI-HSPM-QA-072).

	Substances				
	Cadmium and cadmium compounds				
Heavy metals	Lead and lead compounds				
	Mercury and mercury compounds				
	Hexavalent chromium compounds				
	Polychlorinated biphenyls (PCB)				
Chloinated	Polychlorinated naphthalenes (PCN)				
organic	Polychlorinated terphenyls (PCT)				
compounds	Short-chain chlorinated paraffins(SCCP)				
	Other chlorinated organic compounds				
	Polybrominated biphenyls (PBB)				
Brominated organic	Polybrominated diphenylethers(PBDE) (including				
	decabromodiphenyl ether[DecaBDE])				
compounds	Other brominated organic compounds				
Tributyltin comp	oounds(TBT)				
Triphenyltin con	npounds(TPT)				
Asbestos					
Specific azo com	npounds				
Formaldehyde					
Beryllium oxide					
Beryllium copp	er				
Specific phthalat	tes (DEHP,DBP,BBP,DINP,DIDP,DNOP,DNHP)				
Hydrofluorocarb	on (HFC), Perfluorocarbon (PFC)				
Perfluorooctane	sulfonates (PFOS)				
Specific Benzotr	iazole				

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### **Attachment: Application Guidelines**

### 1.Circuit Design

- 1.1 Operating Temperature and Frequency Electrolytic capacitor electrical parameters are normally specified at 20°C temperature and 120Hz frequency. These parameters vary with changes in temperature and frequency. Circuit designers should take these changes into consideration.
- (1) Effects of operating temperature on electrical parameters
  - a) At higher temperatures, leakage current and capacitance increase while equivalent series resistance (ESR) decreases.
  - b) At lower temperatures, leakage current and capacitance decrease while equivalent series resistance (ESR) increases.
- (2) Effects of frequency on electrical parameters
  - a) At higher frequencies capacitance and impedance decrease while tand increases.
  - b) At lower frequencies, ripple current generated heat will rise due to an increase in equivalent series resistance (ESR).
- 1.2 Operating Temperature and Life Expectancy See the file: Life calculation of aluminum electrolytic capacitor
- 1.3 Common Application Conditions to Avoid

The following misapplication load conditions will cause rapid deterioration to capacitor electrical parameters. In addition, rapid heating and gas generation within the capacitor can occur causing the pressure relief vent to operate and resultant leakage of electrolyte. Under Leaking electrolyte is combustible and electrically conductive.

(1) Reverse Voltage

DC capacitors have polarity. Verify correct polarity before insertion. For circuits with changing or uncertain polarity, use DC bipolar capacitors. DC bipolar capacitors are not suitable for use in AC circuits.

(2) Charge / Discharge Applications

Standard capacitors are not suitable for use in repeating charge / discharge applications. For charge / discharge applications consult us and advise actual conditions.

(3) Over voltage

Do not apply voltages exceeding the maximum specified rated voltage. Voltages up to the surge voltage rating are acceptable for short periods of time. Ensure that the sum of the DC voltage and the superimposed AC ripple voltage does not exceed the rated voltage.

(4) Ripple Current

Do not apply ripple currents exceeding the maximum specified value. For high ripple current applications, use a capacitor designed for high ripple currents or contact us with your requirements. Ensure that allowable ripple currents superimposed on low DC bias voltages do not cause reverse voltage conditions.

- 1.4 Using Two or More Capacitors in Series or Parallel
- (1) Capacitors Connected in Parallel

The circuit resistance can closely approximate the series resistance of the capacitor causing an imbalance of ripple current loads within the capacitors. Careful design of wiring methods can minimize the possibility of excessive ripple currents applied to a capacitor.

(2) Capacitors Connected in Series

Normal DC leakage current differences among capacitors can cause voltage imbalances. The use of voltage divider shunt resistors with consideration to leakage current can prevent capacitor voltage imbalances.

- 1.5 Capacitor Mounting Considerations
- (1) Double Sided Circuit Boards

Avoid wiring pattern runs, which pass between the mounted capacitor and the circuit board.

When dipping into a solder bath, excess solder may collect under the capacitor by capillary action and short circuit the anode and cathode terminals.

(2)Circuit Board Hole Positioning

The vinyl sleeve of the capacitor can be damaged if solder passes through a lead hole for subsequently processed parts. Special care when locating hole positions in proximity to capacitors is recommended.

(3)Circuit Board Hole Spacing

The circuit board holes spacing should match the capacitor lead wire spacing within the specified tolerances. Incorrect spacing can cause excessive lead wire stress during the insertion process. This may result in premature capacitor failure due to short or open circuit, increased leakage current, or electrolyte leakage.

(4) Clearance for Case Mounted Pressure Relief vents

Capacitors with case mounted pressure relief vents require sufficient clearance to allow for proper vent operation. The minimum clearances are dependent on capacitor diameters as proper vent operation. The minimum clearances are dependent on capacitor diameters as follows.

 $\phi 6.3 \text{-} \phi 16 \text{mm:} 2 \text{mm minimum, } \phi 18 \text{-} \phi 35 \text{mm:} 3 \text{mm minimum, } \phi 40 \text{mm or greater:} 5 \text{mm minimum.}$ 

- (5) Clearance for Seal Mounted Pressure Relief Vents
  - A hole in the circuit board directly under the seal vent location is required to allow proper release of pressure.

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(6) Wiring Near the Pressure Relief Vent
Avoid locating high voltage or high current wiring or circuit board paths above the pressure relief vent. Flammable, high temperature gas
exceeding $100^{\circ}$ C may be released which could dissolve the wire insulation and ignite.
(7) Circuit Board patterns Under the Capacitor
Avoid circuit board runs under the capacitor as electrolyte leakage could cause an electrical short.
(8) Screw Terminal Capacitor Mounting
Do not orient the capacitor with the screw terminal side of the capacitor facing downwards.
Tighten the terminal and mounting bracket screws within the torque range specified in the specification.
6
1.6 Electrical Isolation of the Capacitor
Completely isolate the capacitor as follows.
(1) Between the cathode and the case (except for axially leaded B types) and between the anode terminal and other circuit paths
<ul><li>(1) Between the earloade and the ease (except for axially readed b types) and between the anode terminal and other circuit paths</li><li>(2) Between the extra mounting terminals (on T types) and the anode terminal, cathode terminal, and other circuit paths.</li></ul>
(2) Between the extra mounting terminals (on 1 types) and the anode terminal, earloue terminal, and other encurt paths.
1.7. The Product and urange should take the sample as the standard
1.7 The Product endurance should take the sample as the standard.
1.9. If conduct the load or shelf life test, must be collect, date and a within 6 months, products of complian
1.8 If conduct the load or shelf life test, must be collect date code within 6 months products of sampling.
1.9 Capacitor Sleeve
The vinyl sleeve or laminate coating is intended for marking and identification purposes and is not meant to electrically insulate th
capacitor.
The sleeve may split or crack if immersed into solvents such as toluene or xylene, and then exposed to high temperatures.
CAUTION!
Always consider safety when designing equipment and circuits. Plan for worst case failure modes such as short circuits and oper
circuits which could occur during use.
(1) Provide protection circuits and protection devices to allow safe failure modes.
(2) Design redundant or secondary circuits where possible to assure continued operation in case of main circuit failure.
2.Capacitor Handling Techniques
2.1 Considerations Before Using
(1) Capacitors have a finite life. Do not reuse or recycle capacitors from used equipment.
(2) Transient recovery voltage may be generated in the capacitor due to dielectric absorption. If required, this voltage can be discharged
with a resistor with a value of about $1k\Omega$ .
(3) Capacitors stored for long periods of time may exhibit an increase in leakage current. This can be corrected by gradually applying
rated voltage in series with a resistor of approximately $1k\Omega$ .
(4) If capacitors are dropped, they can be damaged mechanically or electrically. Avoid using dropped capacitors.
<ul> <li>(5) Dented or crushed capacitors should not be used. The seal integrity can be compromised and loss of electrolyte / shortened life car</li> </ul>
result.
result.
2.2 Capacitor Insertion
(1) Verify the correct capacitance and rated voltage of the capacitor.
<ul><li>(1) Verify the correct polarity of the capacitor before inserting.</li></ul>
<ul><li>(3) Verify the correct hole spacing before insertion (land pattern size on chip type) to avoid stress on the terminals.</li></ul>
(4) Ensure that the auto insertion equipment lead clinching operation does not stress the capacitor leads where they enter the seal of the
capacitor.
For chip type capacitors, excessive mounting pressure can cause high leakage current, short circuit, or disconnection.
2.3 Manual Soldering
(1) Observe temperature and time soldering specifications or do not exceed temperatures of 400 $^{\circ}$ C for 3 seconds or less.
(2) If lead wires must be formed to meet terminal board hole spacing, avoid stress on the lead wire where it enters the capacitor seal.

(3) If a soldered capacitor must be removed and reinserted, avoid excessive stress to the capacitor leads.

(4) Avoid touching the tip of the soldering iron to the capacitor, to prevent melting of the vinyl sleeve.

2.4 Flow Soldering

(1) Do not immerse the capacitor body into the solder bath as excessive internal pressure could result.

(2) Observe proper soldering conditions (temperature, time, etc.) Do not exceed the specified limits.

(3) Do not allow other parts or components to touch the capacitor during soldering.

2.5 Other Soldering Considerations

Rapid temperature rises during the preheat operation and resin bonding operation can cause cracking of the capacitor vinyl sleeve. For heat curing, do not exceed  $150^{\circ}$ C for a maximum time of 2 minutes.

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- 2.6 Capacitor Handling after Solder
- (1). Avoid movement of the capacitor after soldering to prevent excessive stress on the lead wires where they enter the seal.
- (2). Do not use capacitor as a handle when moving the circuit board assembly.
- (3). Avoid striking the capacitor after assembly to prevent failure due to excessive shock.
- 2.7 Circuit Board Cleaning
- (1) Circuit boards can be immersed or ultrasonically cleaned using suitable cleaning solvents for up 5 minutes and up to  $60^{\circ}$ C maximum temperatures. The boards should be thoroughly rinsed and dried. The use of ozone depleting cleaning agents is not recommended in the interest of protecting the environment.
- (2) Avoid using the following solvent groups unless specifically allowed for in the specification;

Halogenated cleaning solvents: except for solvent resistant capacitor types, halogenated solvents can permeate the seal and cause internal capacitor corrosion and failure. For solvent resistant capacitors, carefully follow the temperature and time requirements of the specification. 1-1-1 trichloroethane should never be used on any aluminum electrolytic capacitor.

- Alkali solvents : could attack and dissolve the aluminum case.
- Petroleum based solvents: deterioration of the rubber seal could result.
- Xylene : deterioration of the rubber seal could result.
- Acetone : removal of the ink markings on the vinyl sleeve could result.
- (3) A thorough drying after cleaning is required to remove residual cleaning solvents which may be trapped between the capacitor and the circuit board. Avoid drying temperatures, which exceed the maximum rated temperature of the capacitor.
- (4) Monitor the contamination levels of the cleaning solvents during use by electrical conductivity, pH, specific gravity, or water content. Chlorine levels can rise with contamination and adversely affect the performance of the capacitor. Please consult us for additional information about acceptable cleaning solvents or cleaning methods.

2.8 Mounting Adhesives and Coating Agents

When using mounting adhesives or coating agents to control humidity, avoid using materials containing halogenated solvents. Also, avoid the use of chloroprene based polymers. After applying adhesives or coatings, dry thoroughly to prevent residual solvents from being trapped between the capacitor and the circuit board.

### 3. Precautions for using capacitors

- 3.1 Environmental Conditions
  - Capacitors should not be stored or used in the following environments.
- (1) Temperature exposure above the maximum rated or below the minimum rated temperature of the capacitor.
- (2) Direct contact with water, salt water, or oil.
- (3) High humidity conditions where water could condense on the capacitor.
- (4) Exposure to toxic gases such as hydrogen sulfide, sulfuric acid, nitric acid chlorine, or ammonia.
- (5) Exposure to ozone, radiation, or ultraviolet rays.
- (6) Vibration and shock conditions exceeding specified requirements.

**3.2 Electrical Precautions** 

- (1) Avoid touching the terminals of the capacitor as possible electric shock could result. The exposed aluminum case is not insulated and could also cause electric shock if touched.
- (2) Avoid short circuit the area between the capacitor terminals with conductive materials including liquids such as acids or alkaline solutions.

### 4. Emergency Procedures

- (1) If the pressure relief vent of the capacitor operates, immediately turn off the equipment and disconnect form the power source. This will minimize additional damage caused by the vaporizing electrolyte.
- (2) Avoid contact with the escaping electrolyte gas which can exceed  $100^{\circ}$ C temperatures.
- If electrolyte or gas enters the eye, immediately flush the eyes with large amounts of water.
  - If electrolyte or gas is ingested by month, gargle with water.
  - If electrolyte contacts the skin, wash with soap and water.

### 5. Long Term Storage

Leakage current of a capacitor increases with long storage times. The aluminum oxide film deteriorates as a function of temperature and time. If used without reconditioning, an abnormally high current will be required to restore the oxide film. This current surge could cause the circuit or the capacitor to fail. After one year, a capacitor should be reconditioned by applying rated voltage in series with a  $1000\Omega$ , current limiting resistor for a time period of 30 minutes. If the expired date of products date code is over eighteen months, the products should be return to confirmation.

5.1 Environmental Conditions



The capacitor shall be not use in the following condition:

(1) Temperature exposure above the maximum rated or below the minimum rated temperature of the capacitor.

(2) Direct contact with water, salt water, or oil.

(3) High humidity conditions where water could condense on the capacitor.

(4) Exposure to toxic gases such as hydrogen sulfide, sulfuric acid, nitric acid, chlorine, or ammonia.

(5) Exposure to ozone, radiation, or ultraviolet rays.

(6) Vibration and shock conditions exceeding specified requirements.

### 6. Capacitor Disposal

When disposing of capacitors, use one of the following methods.

Incinerate after crushing the capacitor or puncturing the can wall (to prevent explosion due to internal pressure rise).

Capacitors should be incinerated at high temperatures to prevent the release of toxic gases such as chlorine from the polyvinyl chloride sleeve, etc.

Dispose of as solid waste.

NOTE: Local laws may have specific disposal requirements, which must be followed.

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